



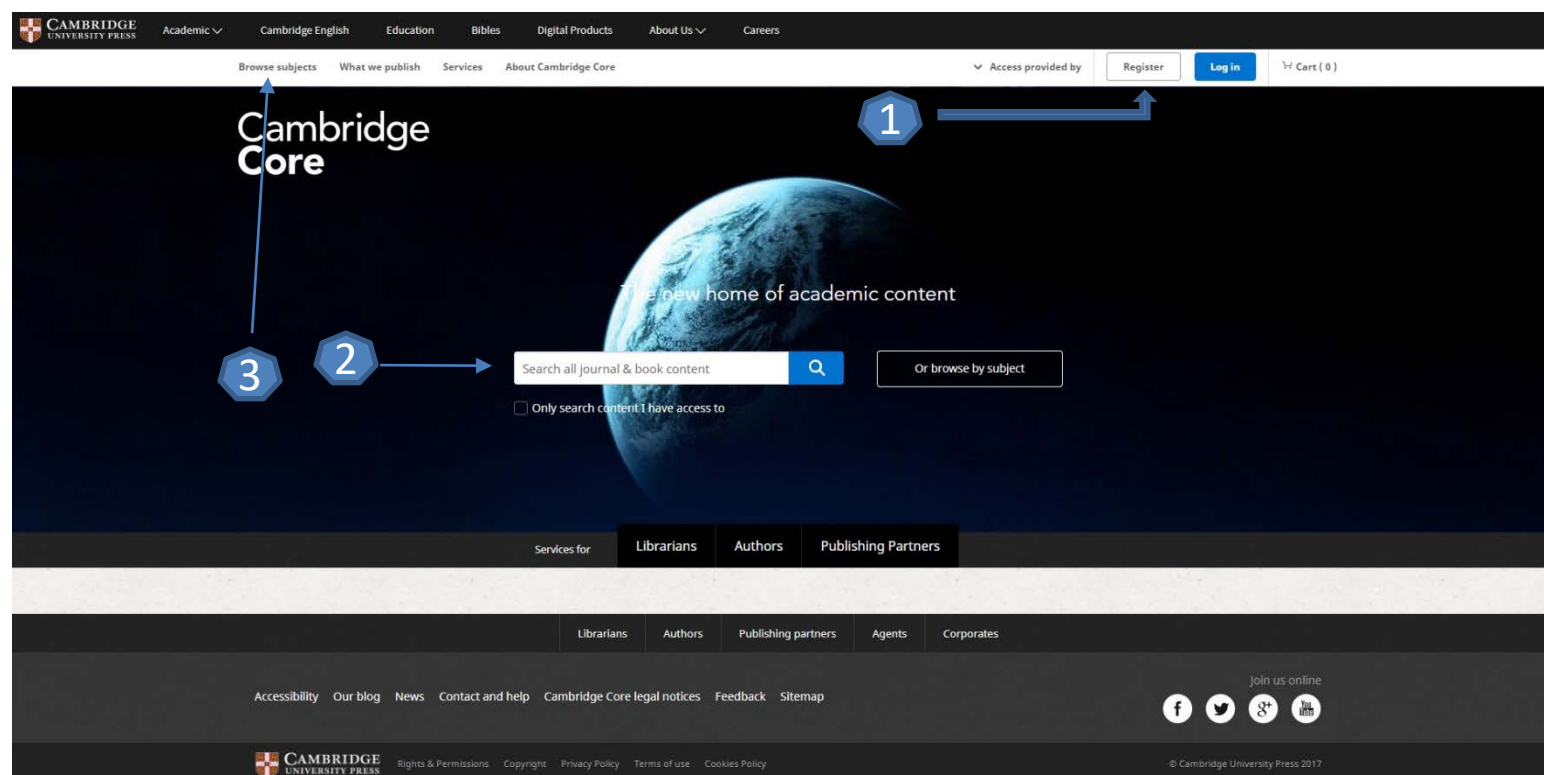
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Ghid de utilizare



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- ❑ Înregistrarea și utilizarea unui cont personal 1.
- ❑ Motorul de căutare în modul de bază, cu posibilitatea de a selecta modul de căutare avansată 2.
- ❑ Accesarea listelor 3: lista de titluri, lista de domenii, lista de reviste favorite etc.



The screenshot shows the Cambridge Core website interface. The top navigation bar includes links for Academic, Cambridge English, Education, Bibles, Digital Products, About Us, and Careers. The main header area features the Cambridge Core logo, navigation links (Browse subjects, What we publish, Services, About Cambridge Core), and user options (Access provided by, Register, Log in, Cart (0)). The main content area has a large banner with the text 'The new home of academic content' and a search bar. Three numbered annotations are present: 1 points to the 'Register' button, 2 points to the search bar, and 3 points to the 'Browse subjects' link. The bottom section includes a 'Services for' dropdown menu with options for Librarians, Authors, and Publishing Partners, followed by a footer with various links and social media icons.

Advanced Search

Enter your search criteria below, using the drop down boxes to define your search or run one of [My Saved/Recent Searches](#). Empty "Search for" fields will not be included in the search. Click [here](#) for help.

☒ Search All Journal and Book Content ☐ Search All Journals Only

Search on	Search for	
Anywhere		AND
Full Text		AND
Article or Chapter Title		AND
Author or Editor		AND
Abstract		

☐ Search exact phrase
☐ Search Open Access articles only

By Date

From
To

Fields to Be Returned

Article Title

Article Subtitle

Author(s)

Journal Title

Volume No.

Issue No.

Issue Date

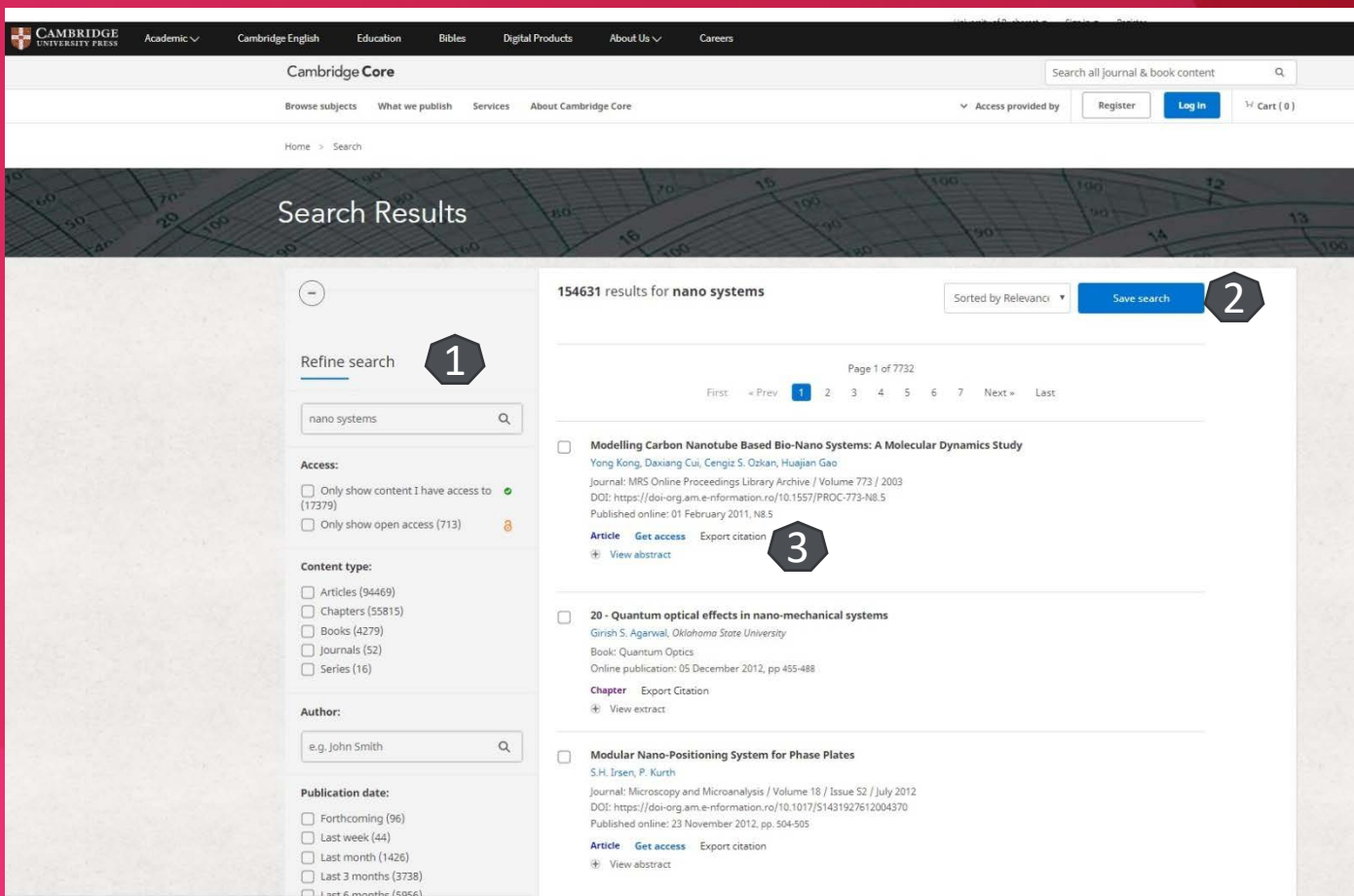
DOI

Publication Date

- ❑ Motorul de căutare avansată permite căutarea de documente, în funcție de diferite criterii. Pentru început, se vor completa câmpurile destinate cuvintelor-cheie, se vor crea legături între ele prin operatori logici, iar apoi se va selecta unul dintre criteriile după care se va face căutarea.
- ❑ Pentru a rafina căutarea, se vor selecta revistele sau domeniile din care să facă parte cuvintele-cheie.
- ❑ De asemenea, căutarea avansată permite selectarea unui interval temporal sau a tipului de document, precum și alte criterii.

Lista de rezultate

- ☐ Rezultatele căutării pot fi sortate după diferite criterii 1.
- ☐ Rezultatele obținute se pot salva 2.
- ☐ Prin selectarea articolelor de interes, se pot exporta totodată și referințele aferente lor 3.

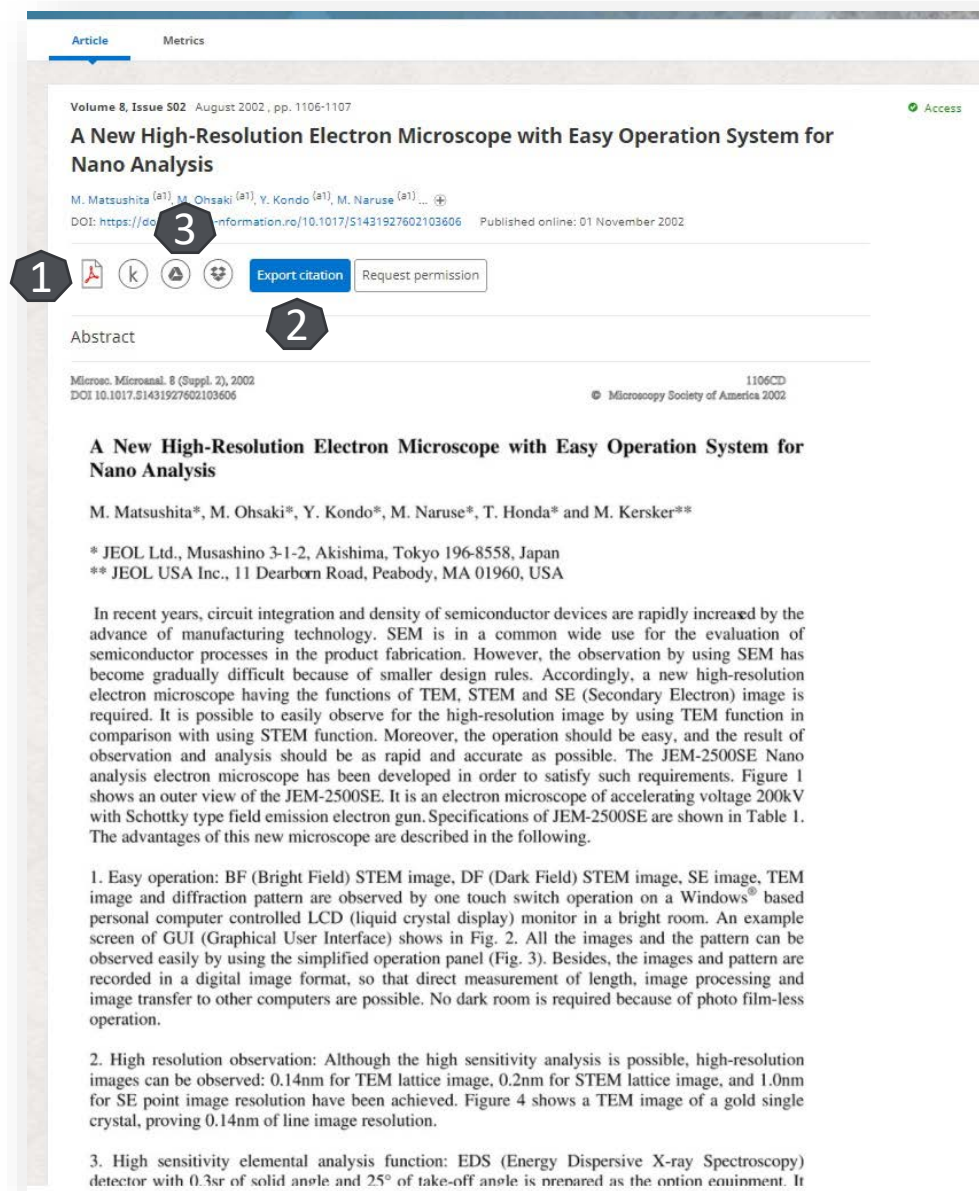


The screenshot displays the Cambridge Core search results page for the query "nano systems". The page is annotated with three numbered callouts:

- 1** Points to the "Refine search" sidebar on the left, which includes filters for "Access" (Only show content I have access to (17379), Only show open access (713)), "Content type" (Articles (94469), Chapters (55815), Books (4279), Journals (52), Series (16)), "Author" (e.g. John Smith), and "Publication date" (Forthcoming (96), Last week (44), Last month (1426), Last 3 months (3738), Last 6 months (6066)).
- 2** Points to the "Save search" button located next to the "Sorted by Relevance" dropdown menu.
- 3** Points to the "Article" link for the first search result, "Modelling Carbon Nanotube Based Bio-Nano Systems: A Molecular Dynamics Study".

The search results list shows 154631 results for "nano systems". The first result is "Modelling Carbon Nanotube Based Bio-Nano Systems: A Molecular Dynamics Study" by Yong Kong, Daxiang Cui, Cengiz S. Ozkan, and Huajian Gao. The second result is "20 - Quantum optical effects in nano-mechanical systems" by Girish S. Agarwal, Oklahoma State University. The third result is "Modular Nano-Positioning System for Phase Plates" by S.H. Irsen, P. Kurth.

Pagina dedicată articolului



The screenshot shows a journal article page with the following elements:

- Callout 1:** Points to the article title and author information at the top of the page.
- Callout 2:** Points to the abstract section, which includes the journal name, volume, issue, and page numbers.
- Callout 3:** Points to the 'Export citation' button, which is located next to the article title and author information.

Article Information:

Volume 8, Issue 502 August 2002, pp. 1106-1107

A New High-Resolution Electron Microscope with Easy Operation System for Nano Analysis

M. Matsushita^(a1), M. Ohsaki^(a1), Y. Kondo^(a1), M. Naruse^(a1) ...

DOI: <https://doi.org/10.1017/S1431927602103606> Published online: 01 November 2002

Abstract

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DOI 10.1017/S1431927602103606 © Microscopy Society of America 2002

A New High-Resolution Electron Microscope with Easy Operation System for Nano Analysis

M. Matsushita*, M. Ohsaki*, Y. Kondo*, M. Naruse*, T. Honda* and M. Kersker**

* JEOL Ltd., Musashino 3-1-2, Akishima, Tokyo 196-8558, Japan
** JEOL USA Inc., 11 Dearborn Road, Peabody, MA 01960, USA

In recent years, circuit integration and density of semiconductor devices are rapidly increased by the advance of manufacturing technology. SEM is in a common wide use for the evaluation of semiconductor processes in the product fabrication. However, the observation by using SEM has become gradually difficult because of smaller design rules. Accordingly, a new high-resolution electron microscope having the functions of TEM, STEM and SE (Secondary Electron) image is required. It is possible to easily observe for the high-resolution image by using TEM function in comparison with using STEM function. Moreover, the operation should be easy, and the result of observation and analysis should be as rapid and accurate as possible. The JEM-2500SE Nano analysis electron microscope has been developed in order to satisfy such requirements. Figure 1 shows an outer view of the JEM-2500SE. It is an electron microscope of accelerating voltage 200kV with Schottky type field emission electron gun. Specifications of JEM-2500SE are shown in Table 1. The advantages of this new microscope are described in the following.

1. Easy operation: BF (Bright Field) STEM image, DF (Dark Field) STEM image, SE image, TEM image and diffraction pattern are observed by one touch switch operation on a Windows® based personal computer controlled LCD (liquid crystal display) monitor in a bright room. An example screen of GUI (Graphical User Interface) shows in Fig. 2. All the images and the pattern can be observed easily by using the simplified operation panel (Fig. 3). Besides, the images and pattern are recorded in a digital image format, so that direct measurement of length, image processing and image transfer to other computers are possible. No dark room is required because of photo film-less operation.

2. High resolution observation: Although the high sensitivity analysis is possible, high-resolution images can be observed: 0.14nm for TEM lattice image, 0.2nm for STEM lattice image, and 1.0nm for SE point image resolution have been achieved. Figure 4 shows a TEM image of a gold single crystal, proving 0.14nm of line image resolution.

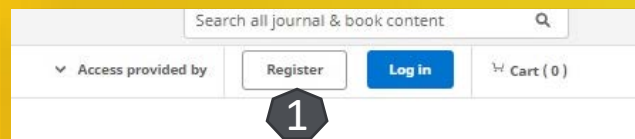
3. High sensitivity elemental analysis function: EDS (Energy Dispersive X-ray Spectroscopy) detector with 0.3sr of solid angle and 25° of take-off angle is prepared as the option equipment. It

De pe pagina de rezultate, printr-un click pe titlul unui articol, se va ajunge la pagina dedicată acestuia.

- ❑ Accesul la articolul integral, în format PDF 1.
- ❑ Exportul referinței, în format BibTEX, Endnote, RefWorks 2.
- ❑ Exportul articolului către Kindle, Google Drive sau Dropbox 3.

Creare cont personal

- ❑ Pentru a beneficia de posibilitatea salvării întregului parcurs de căutare sau de activarea unei alerte de înștiințare despre apariția unui nou articol corespunzător ultimelor filtre de analiză selectate, trebuie activat un cont personal, din tab-ul „Register” 1. La apariția casetei 2, se completează formularul. La finalul formularului se apasă tab-ul „Register” și trebuie verificat e-mail-ul declarat, pentru confirmarea adresei. După confirmare, contul devine activ 3.



Register 2

Title: <Select> Country *: <Select>

First name *: Enter your first name Organisation *: Enter your organisation name ☐ No affiliation

Last name *: Enter your last name Password *: Enter your password

Email *: Enter your email Confirm password *: Confirm your password

ORCID iD (if applicable) ⓘ Enter your ORCID iD, e.g. 0000-0001-0001-0035

CAPTCHA *: Click or touch the **Tree**

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☐ By creating your account you agree to our [Terms of use](#) and confirm that you are at least 16 years of age. *
☐ Please keep me informed by email about relevant Cambridge publishing, news and special offers.

Cancel Register

3

Thank you for registering with Cambridge Core. You can now log in to access your account. ✕

Întrebări și sugestii:

iulian.tanea@enformation.ro

Strada Vasile Lascăr, nr. 179, sector 2,
020498, București

Telefon: +40212102096



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